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of the scintillating material. Further, if a raster dither pattern or the like is used the pitch of the raster lines must not exceed stripe width in order to assure reliable detection.

In the claims: /

Please amend claim 3, as follows: /

Ab

3. A method as recited in claim 1, including the further steps of
passing said charged particle beam through a first shaping aperture,
deflecting said charged particle beam, and
intercepting a portion of said charged particle beam with a second shaping aperture while
shaping a remainder of said charged particle beam passed through said second shaping aperture.

Remarks

Claims 1 - 20 remain in the instant application. The instant invention is drawn to a method for operating a charged particle beam tool. All of objections to specification should be withdrawn as all of the amendments requested by the Examiner have been accomplished. An appendix showing the relevant sections of the specification in marked up form is attached.

The rejection of any of claims 1 - 20 under any section of 35 USC 103 using Katsap

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